

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Continuation Patent Application of )  
Satoshi SHIBATA et al. )  
Based On Application No. 09/984,908 ) Art Unit: 2859  
Which Was Filed: October 31, 2001 ) Examiner: Pruchnic  
For: METHOD FOR PREDICTING TEMPERATURE, )  
TEST WAFER FOR USE IN TEMPERATURE )  
PREDICTION, AND METHOD FOR EVALUATING )  
LAMP HEATING SYSTEM ) Date: June 23, 2003

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98.

The references listed on the attached Form PTO-1449 were cited in parent application Serial No. 09/984,908 filed October 31, 2001, from which priority is claimed under 35 U.S.C. 120.

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

By: \_\_\_\_\_

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Substitute for form 1449A/PTO				<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	740819-1016
				Filing Date	June 23, 2003
				First Named Inventor	Satoshi SHIBATA et al.
				Art Unit	2859
				Examiner Name	S. Pruchnic
Sheet	1	of	1	Attorney Docket Number	740819-1016

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)			
		US-6,132,081	10/17/2000	Han	
		US-6,022,749	02/08/2000	Davis et al.	
		US-5,902,504	05/11/1999	Merchant et al.	
		US-5,265,957	11/30/1993	Moslehi et al.	
		US-6,299,346 B1	10/09/2001	Ish-Shalom et al.	
		US-6,475,815 B1	11/05/2002	Nambu et al.	
		US-6,472,232 B1	10/29/2002	Johnson et al.	
		US-6,200,023 B1	03/13/2001	Tay et al.	
		US-6,128,084	10/03/2000	Nanbu et al.	
		US-6,126,744	10/03/2000	Hawkins et al.	
		US-5,994,676	11/30/1999	Dutartre	
		US-5,769,540	06/23/1998	Schietinger et al.	
		US-4,786,608	11/22/1998	Griffith	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Kind Code <sup>3</sup> Country Code <sup>3</sup> Number <sup>4</sup> (if known)				
		WO 98/57146 A1	12/17/1998			Abstract

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		Fried, M., et al., "Optical properties of thermally stabilized ion implantation amorphized silicon," Nuclear Instruments and Methods in Physics Research, B19/20, North-Holland, Amsterdam (1987) 577-581.	
		Csepregi, L., et al., "Reordering of amorphous layers of Si implanted with 31P and 75As, and 11B ions," Journal of Applied Physics (Oct. 1977) Vol. 48, No. 10, pp. 4234-40.	

Examiner Signature	Date Considered
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.